

Life Expectancy Report

Representative Test Model : S8038-7K

◎ L_{10} Expectancy: 72,000 hours minimum @ fan rated voltage and the temperature of 40°C According to the equation for Weibull distribution, MTTF = 7× L_{10} = 504,000 hours And we rely on a zero failure Weibull test strategy and accelerated testing technique, to determine the total test time (t) for verifying the above life estimation by the equations,

 $t = 1.036 \times MTTF \times [(B_{r,c}) \div n]^{0.91} \div A_F$, and $A_F = 2^{(Ts-Tu)/10}$

where, $(B_{r;c})$ is Poisson distribution factor with the failure number of r equal to 0 and the decimal confidence level of c equal to 0.90(90%), and

Stress/Elevated Temperature Ts (°C)	Unstress Temperature Tu (°C)	Acceleration Factor A _F	Quantity of Test Devices n (pcs)	Possion Distribution Factor B _{r;c}	Required test time with zero failure t (hours)	Actual test time with zero failure t (hours)	Verified MTTF (hours)	Verified L ₁₀ (hours)
75	40	11.31	40	2.303	3,436	3,456.0	506,998	72,428

Test Progress:

Date for Test	Date for Test		Curr	rent Test Status		Current Total Test		
Beginning	l erminatio	n (at least)	-			Time (hours)		
2023/7/15 12:00 AM	2023/12/6	12:00 AM	□ In process	In process (exceed requested)	 ✓ Termination 	3456.0		
INSPECTION CRITERIA : 1.Current (Icc) variation fro	: om nominal : +	⊦/- 30%	Temperature for MTTF Estimation (℃)	Acceleration Factor A _F	Estimated MTTF (hours)	Estimated L ₁₀ (hours)		
2.Rotational Speed variation	on from nomin	al : +/- 30%	30	22.63	1,013,996	144,857		
4.Inspecting external if the	re is any defe	cts in fan	40	11.31	506,998	72,428		
5.Using the lowest voltage	to inspect if it	ne ran still op	50	5.66	253,499	36,214		
			60	2.83	126,749	18,107		
			70	1.41	63,375	9,054		
			80	0.71	31,687	4,527		
			90	0.35	15,844	2,263		
			Herewith , we could assume as right on the basis of above test result. Besides, if the actual test time exceed the required, it comes out that those fans' L10 expectancy and MTTF are greater than the warrant.					
Time-out for function test or others (hours)	Issued Date	Appro	ved By	Review		Reported By		
	2023/12/08					Hongy	e Lai	